## Notice of References Cited Application/Control No. 10/789,467 Examiner Binh-An D. Nguyen Applicant(s)/Patent Under Reexamination STELZER ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0019984	02-2002	Rakib, Selim Shlomo	725/111
	В	US-6,921,336 B1	07-2005	Best, Robert M.	463/32
	С	US-5,999,808	12-1999	LaDue, Christoph Karl	455/412.2
	D	US-6,872,139 B2	03-2005	Sato et al.	463/39
-	E	US-5,855,483 A	01-1999	Collins et al.	434/322
	F	US-6,008,777 A	12-1999	Yiu, Timothy C.	345/2.1
	G	US-6,907,029 B2	06-2005	Brabrand, Tord	370/347
	Н	US-2003/0104865 A1	06-2003	Itkis et al.	463/39
	1	US-5,695,400	12-1997	Fennell et al.	463/42
	J	US-5,702,305	12-1997	Norman et al.	463/42
	К	US-6,524,189 B1	02-2003	Rautila, Heikki	463/40
	L	US-6,874,003 B2	03-2005	Morohashi, Akihiro	707/204
	М	US-5,881,366 A	03-1999	Bodenmann et al.	455/41.2

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.